FAIRCHILD SEMICONDUCTOR™

July 1988
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100350
Low Power Hex D-Type Latch

General Description

The 100350 contains six D-type latches with true and complement outputs, a pair of common Enables ($\overline{E}_a$ and $\overline{E}_b$), and a common Master Reset (MR). A Q output follows its D input when both $\overline{E}_a$ and $\overline{E}_b$ are LOW. When either $\overline{E}_a$ or $\overline{E}_b$ (or both) are HIGH, a latch stores the last valid data present on its D input before $\overline{E}_a$ or $\overline{E}_b$ went HIGH. The MR input overrides all other inputs and makes the Q outputs LOW. All inputs have 50 kΩ pull-down resistors.

Features

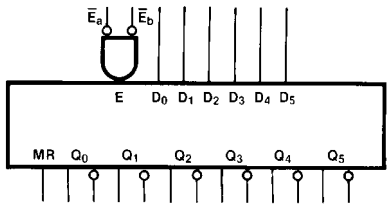
- 20% power reduction of the 100150
- 2000V ESD protection
- Pin/function compatible with 100150
- Voltage compensated operating range = –4.2V to –5.7V

Ordering Code:

Order Number	Package Number	Package Description
100350PC	N24E	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-010, 0.400 Wide
100350QC	V28A	28-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.450 Square

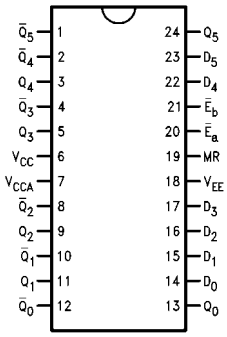
Devises also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol

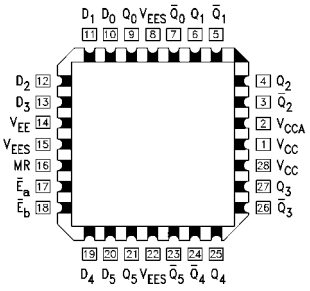


Connection Diagrams

24-Pin DIP



28-Pin PLCC



Pin Descriptions

Pin Names	Description
D_0–D_5	Data Inputs
$\overline{E}_a$, $\overline{E}_b$	Common Enable Inputs (Active LOW)
MR	Asynchronous Master Reset Input
Q_0–Q_5	Data Outputs
$\overline{Q}_0$–$\overline{Q}_5$	Complementary Data Outputs

Truth Tables

(Each Latch)

Latch Operation

Inputs				Outputs
D_n	$\overline{E}_a$	$\overline{E}_b$	MR	Q_n
L	L	L	L	L
H	L	L	L	H
X	H	X	L	Latched (Note 1)
X	X	H	L	Latched (Note 1)

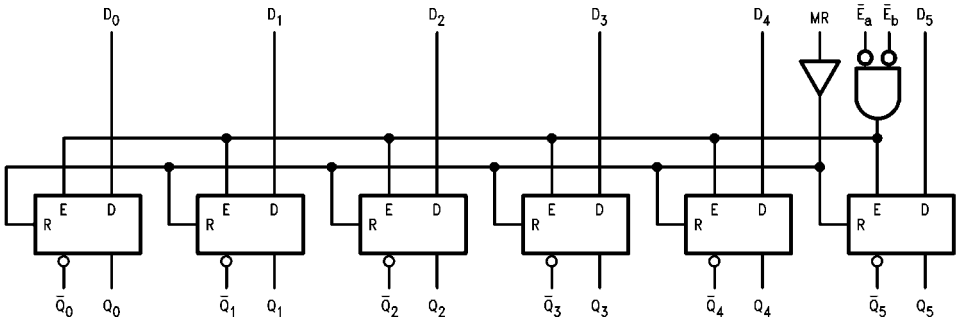
Asynchronous Operation

Inputs				Outputs
D_n	$\overline{E}_a$	$\overline{E}_b$	MR	Q_n
X	X	X	H	L

H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care

Note 1: Retains data present before $\overline{E}$ positive transition

Logic Diagram



Absolute Maximum Ratings (Note 2)

Above which the useful life may be impaired.

Storage Temperature (T_{STG})	−65°C to +150°C
Maximum Junction Temperature (T_J)	+150°C
V_{EE} Pin Potential to Ground Pin	−7.0V to +0.5V
Input Voltage (DC)	V_{EE} to +0.5V
Output Current (DC Output HIGH)	−50 mA
ESD (Note 3)	≥2000V

Recommended Operating Conditions

Case Temperature (T_C)	0°C to +85°C
Supply Voltage (V_{EE})	−5.7V to −4.2V

Note 2: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum rating. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 3: ESD testing conforms to MIL-STD-883, Method 3015.

DC Electrical Characteristics (Note 4)

V_{EE} = −4.5V to −5.7V, V_{CC} = V_{CCA} = GND, T_C = 0°C to +85°C

Symbol	Parameter	Min	Typ	Max	Units	Conditions	
V_{OH}	Output HIGH Voltage	−1025	−955	−870	mV	V_{IN} = $V_{IH\ (Max)}$	Loading with
V_{OL}	Output LOW Voltage	−1830	−1705	−1620		or $V_{IL\ (Min)}$	50Ω to −2.0V
V_{OHC}	Output HIGH Voltage	−1035			mV	V_{IN} = $V_{IH\ (Min)}$	Loading with
V_{OLC}	Output LOW Voltage			−1610		or $V_{IL\ (Max)}$	50Ω to −2.0V
V_{IH}	Input HIGH Voltage	−1165		−870	mV	Guaranteed HIGH Signal for All Inputs	
V_{IL}	Input LOW Voltage	−1830		−1475	mV	Guaranteed LOW Signal for All Inputs	
I_{IL}	Input LOW Current	0.50			µA	V_{IN} = $V_{IL\ (Min)}$	
I_{IH}	Input HIGH Current MR			240	µA	V_{IN} = $V_{IH\ (Max)}$	
	D_n			240			
	$\overline{E}_a$, $\overline{E}_b$			240			
I_{EE}	Power Supply Current				mA	Inputs Open	
		−89		−44		V_{EE} = −4.2V to −4.8V	
		−93		−44		V_{EE} = −4.2V to −5.7V	

Note 4: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guard banding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

DIP AC Electrical Characteristics

V_{EE} = −4.2V to −5.7V, V_{CC} = V_{CCA} = GND

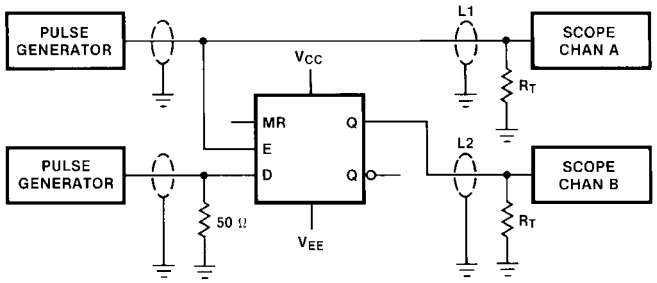
Symbol	Parameter	T_C = 0°C		T_C = +25°C		T_C = +85°C		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH}	Propagation Delay								
t_{PHL}	D_n to Output	0.50	1.40	0.50	1.40	0.50	1.50	ns	
	(Transparent Mode)								Figures 1, 2
t_{PLH}	Propagation Delay	0.75	1.85	0.75	1.85	0.75	2.05	ns	
t_{PHL}	$\overline{E}_a$, $\overline{E}_b$ to Output								
t_{PLH}	Propagation Delay	0.90	2.10	0.90	2.10	0.90	2.10	ns	Figures 1, 3
t_{PHL}	MR to Output								
t_{TLH}	Transition Time	0.35	1.30	0.35	1.30	0.35	1.30	ns	Figures 1, 2
t_{THL}	20% to 80%, 80% to 20%								
t_S	Setup Time								
	D_0–D_5	1.00		1.00		1.00		ns	Figures 3, 4
	MR (Release Time)	1.60		1.60		1.60			
t_H	Hold Time, D_0–D_5	0.40		0.40		0.40		ns	Figure 4
t_{PW}(L)	Pulse Width LOW	2.00		2.00		2.00		ns	Figure 2
	$\overline{E}_a$, $\overline{E}_b$								
t_{PW}(H)	Pulse Width HIGH, MR	2.00		2.00		2.00		ns	Figure 3

PLCC AC Electrical Characteristics

V_{EE} = –4.2V to –5.7V, V_{CC} = V_{CCA} = GND

Symbol	Parameter	T_C = 0°C		T_C = +25°C		T_C = +85°C		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_{PLH} t_{PHL}	Propagation Delay D_n to Output (Transparent Mode)	0.50	1.20	0.50	1.20	0.50	1.30	ns	Figures 1, 2
t_{PLH} t_{PHL}	Propagation Delay $\overline{E}_a$, $\overline{E}_b$ to Output	0.75	1.65	0.75	1.65	0.75	1.85	ns	
t_{PLH} t_{PHL}	Propagation Delay MR to Output	0.90	1.90	0.90	1.90	0.90	1.90	ns	Figures 1, 3
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	Figures 1, 2
t_S	Setup Time D_0–D_5 MR (Release Time)	0.90 1.50		0.90 1.50		0.90 1.50		ns	Figures 3, 4
t_H	Hold Time, D_0–D_5	0.30		0.30		0.30		ns	Figure 4
t_{PW}(L)	Pulse Width LOW $\overline{E}_a$, $\overline{E}_b$	2.00		2.00		2.00		ns	Figure 2
t_{PW}(H)	Pulse Width HIGH, MR	2.00		2.00		2.00		ns	Figure 3

Test Circuit



Note:

- V_{CC}, V_{CCA} = +2V, V_{EE} = –2.5V
- L1 and L2 = equal length 50Ω impedance lines
- R_T = 50Ω terminator internal to scope
- Decoupling 0.1 µF from GND to V_{CC} and V_{EE}
- All unused outputs are loaded with 50Ω to GND
- C_L = Fixture and stray capacitance ≤ 3 pF

FIGURE 1. AC Test Circuit

Switching Waveforms

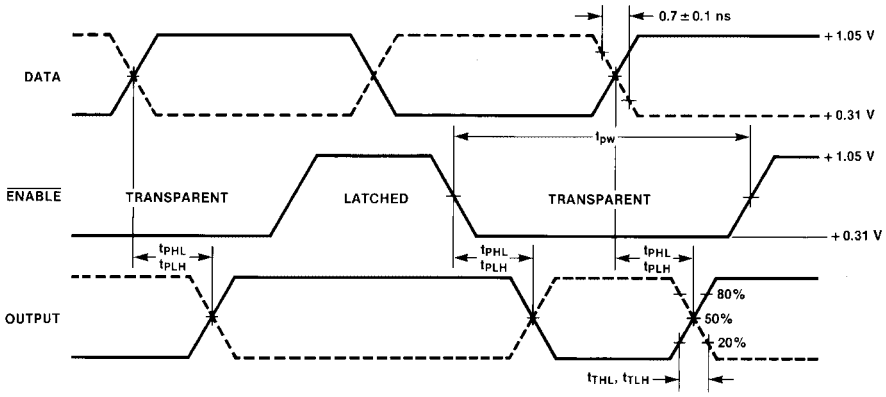


FIGURE 2. Enable Timing

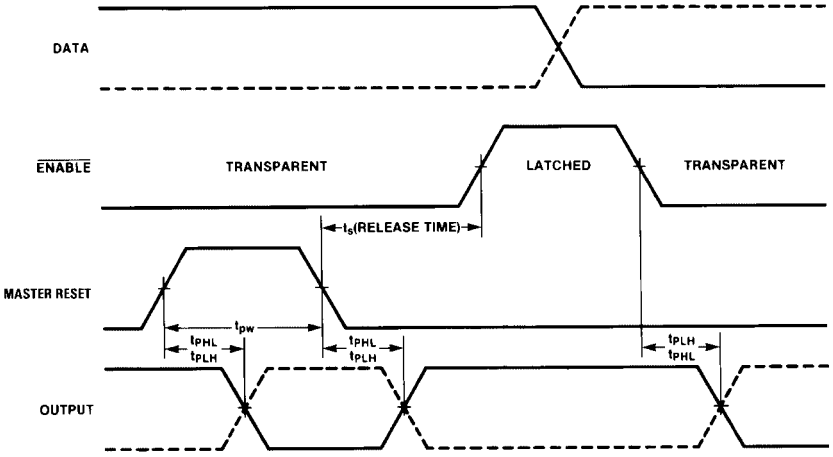
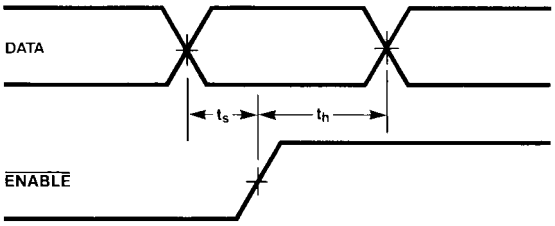


FIGURE 3. Reset Timing



Notes:

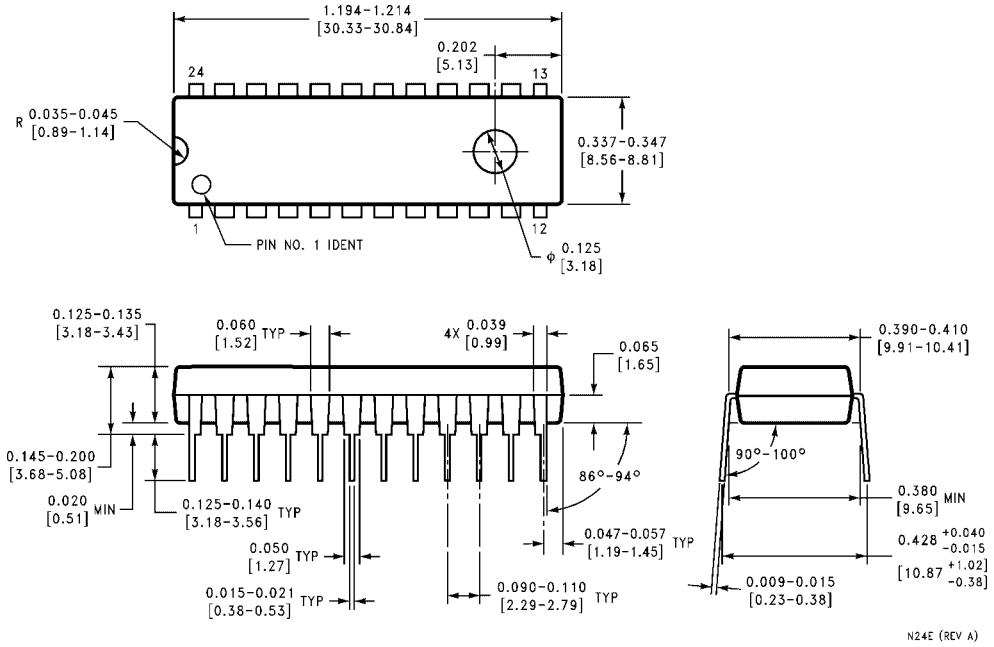
t_S is the minimum time before the transition of the enable that information must be present at the data input.

t_H is the minimum time after the transition of the enable that information must remain unchanged at the data input.

FIGURE 4. Data Setup and Hold Time

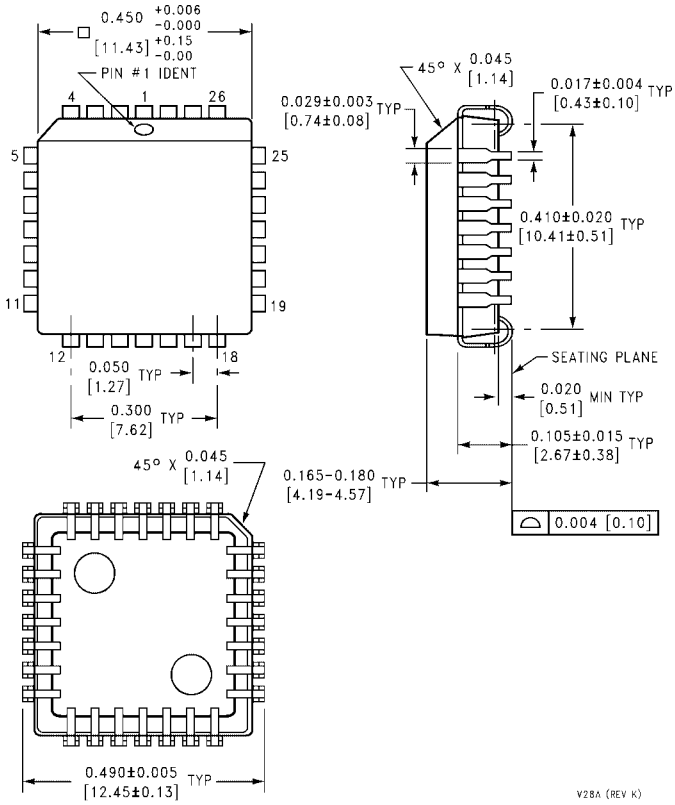
100350

Physical Dimensions inches (millimeters) unless otherwise noted



24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-010, 0.400 Wide
Package Number N24E

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



28-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.450 Square
Package Number V28A

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